

Appli	cation	/Contro	l No.

Applicant(s)/Patent under Reexamination

10/535,428

Examiner

FLAMANG ET AL. Art Unit

Devin Hanan

3745

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Class	Subclass	Date	Examiner
415	4.3, 4.4		
	4.5, 70		
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416	170R	10/30/2006	DH
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